

# Development of the non-invasive beam size monitor using ODR

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# Introduction

For the ultra-low emittance and high intensity electron beam required by Linear Colliders and X-ray FEL, conventional beam diagnostics (OTR monitor, solid wire scanner, etc.) are not applied to such beams because of the target destruction. Therefore non-invasive beam diagnostics is necessary techniques for such accelerators.

Because of non-invasive nature, Diffraction radiation(DR) is one of candidates for application to non-invasive beam diagnostic.

However a very little experimental investigations existed.

Those experiments are measurements of coherent diffraction radiation( $\lambda \sim 1$  mm), incoherent diffraction radiation with visible light region(Optical Diffraction Radiation :ODR) hadn't been observed.

Since 2000, we have performed ODR experiments using low emittance electron beam extracted from KEK-ATF damping ring.

At first stage experiments, we confirmed basic characteristics of ODR from the single edge target.  
( T. Muto *et al.* , Phys. Rev. Lett 90,104801(2003) )

Now we have developed the beam size monitor using ODR.



# Principle of the ODR monitor

## Optical Diffraction Radiation

The ODR appears when the charged particle passes near media with different dielectric constant.

ODR is emitted to two direction

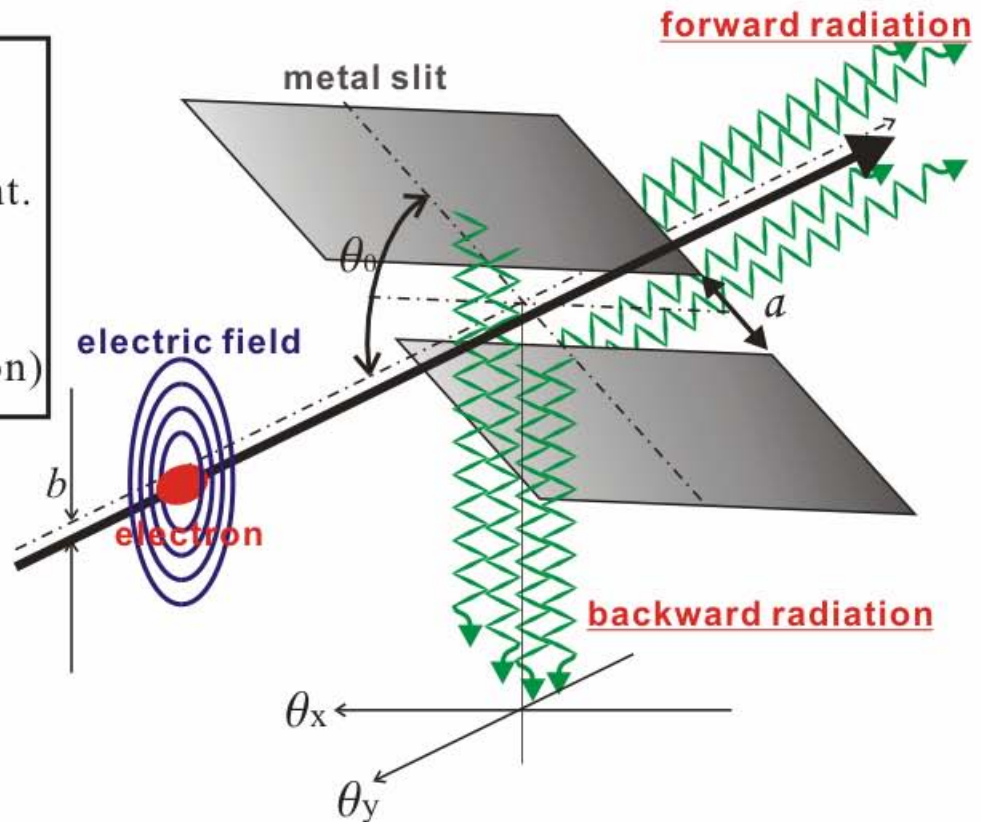
- along the particle (forward radiation)
- direction of reflection (backward radiation)

## Beam size measurement using ODR

use the interference of ODRs from two halves of the slit target

## Features of ODR monitor

- non-invasive
- one-shot measurements
- large observation angle
- good time resolution





# Principle (Cont.)

Angular distribution of the vertical polarization component of ODR

$$\frac{dW_y}{d\omega d\Omega} = \frac{\alpha\gamma^2}{2\pi^2} \frac{\exp\left(-\frac{2\pi a \sin\theta_0}{\gamma\lambda} \sqrt{1+t_x^2}\right)}{1+t_x^2+t_y^2}$$

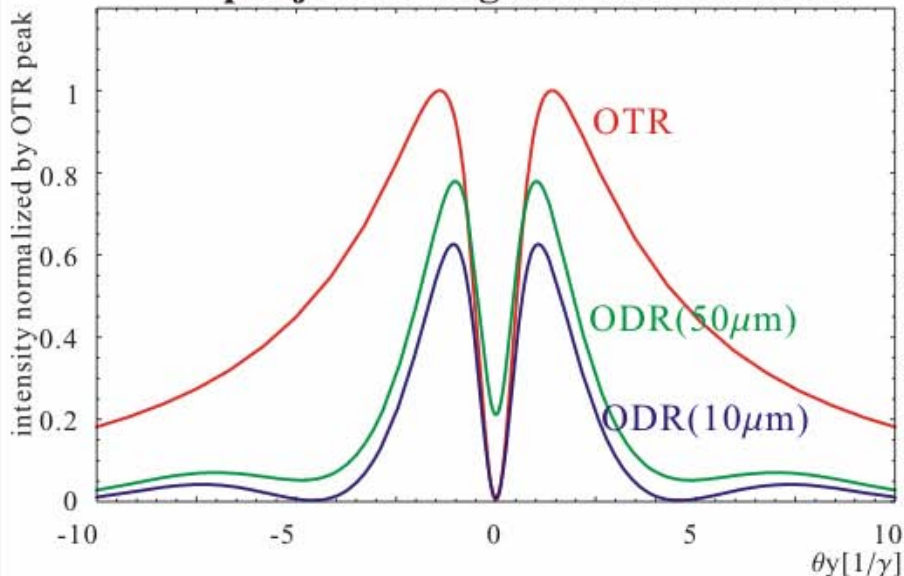
$$t_{x,y} = \gamma\theta_{x,y} \quad \psi = \arccos \frac{1+t_x^2-t_y^2}{1+t_x^2+t_y^2}$$

$$\left\{ \exp\left(\frac{8\pi^2}{\gamma^2\lambda^2} \sigma_y^2 (1+t_x^2)\right) \cosh\left(\frac{4\pi b}{\gamma\lambda} \sqrt{1+t_x^2}\right) - \cos\left(\frac{2\pi a \sin\theta_0}{\gamma\lambda} t_y + \psi\right) \right\}$$

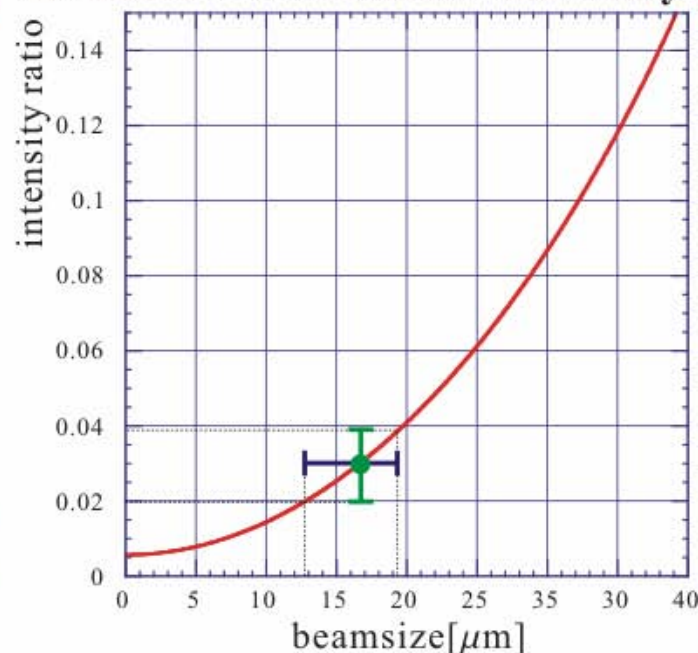
(assume the beam has Gaussian distribution)

In order to increase the signal,  
we take integrate to the horizontal angle

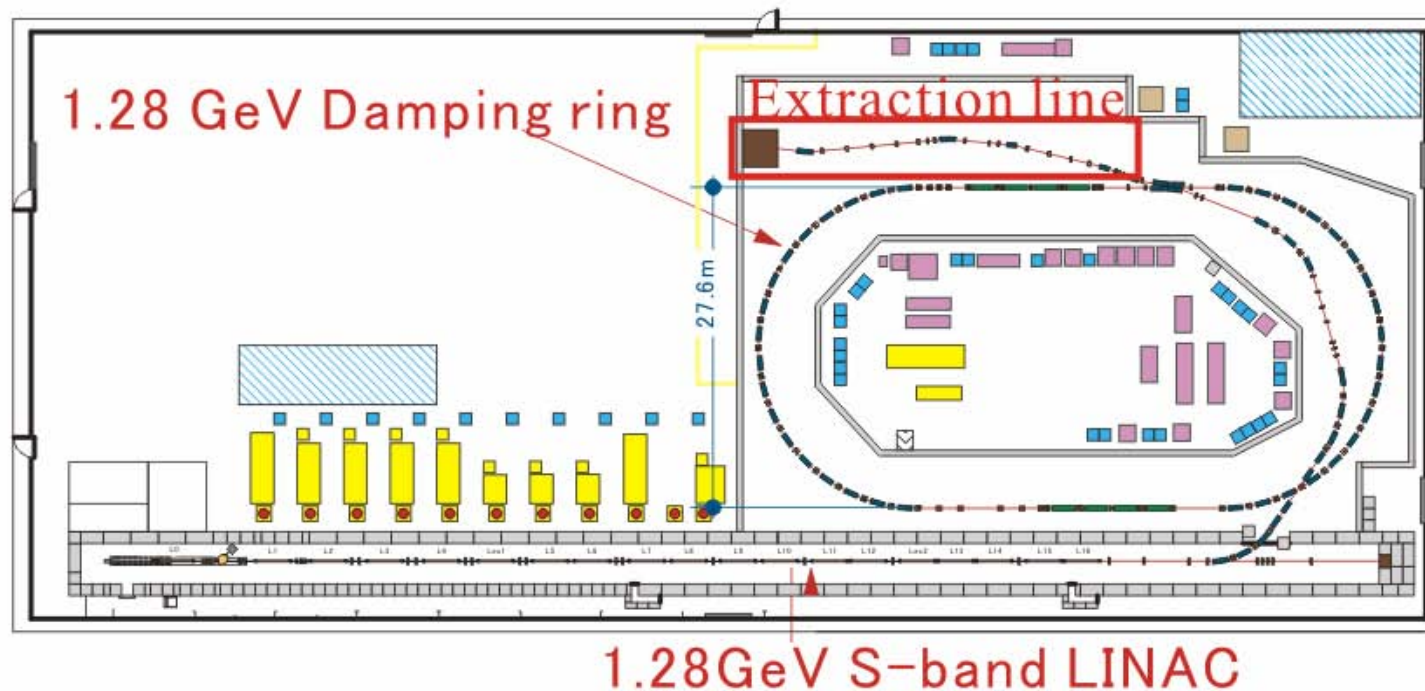
**projected angular distribution**



**beam size vs  
minimum-to-maximum intensity ratio**



# KEK-ATF (Accelerator Test Facility)



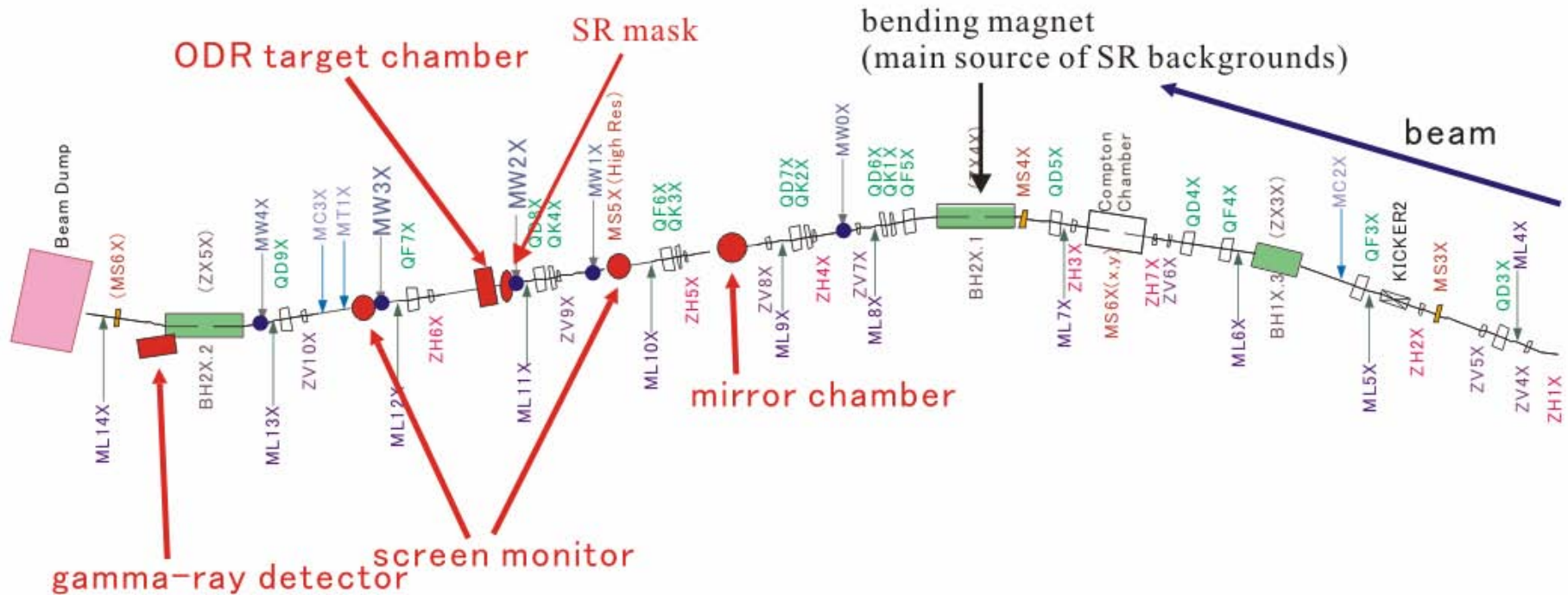
KEK-ATF parameter  
energy 1.28 GeV ( $\gamma \sim 2500$ )

emittance    vertical     $\sim 5$  pm rad  
                 horizontal     $\sim 1$  nm rad

bunch length 20 ps

intensity  
 $1.2 \times 10^{10}$  electrons/bunch

# Layout of the extraction line



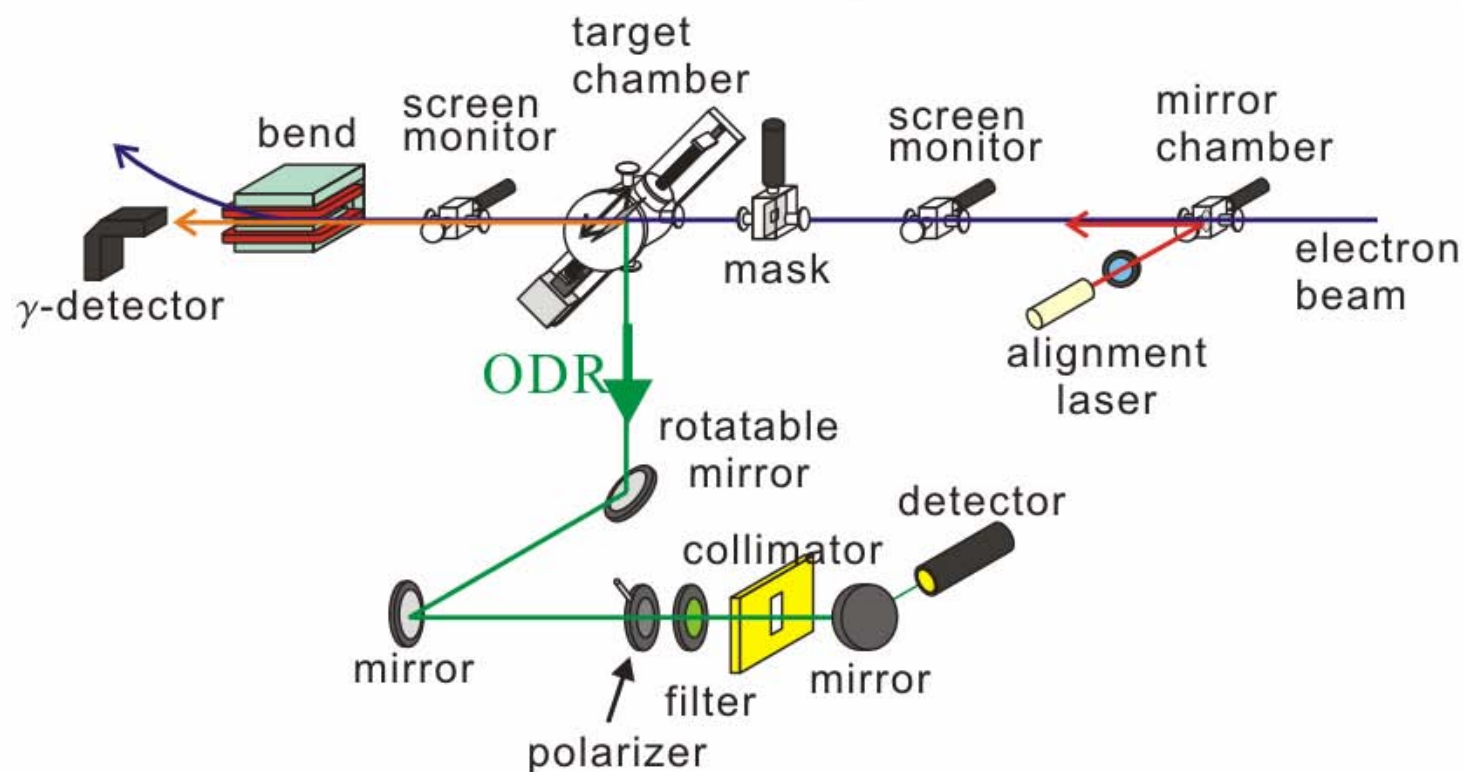
The emittance can be measured by 5 wire scanners.

At the ODR measurements,  
emittance measurements was done.

Using measured parameters,  
the optics for ODR measurements was calculated by SAD.



# Schematic view of the experimental set up



collimator size:  $v\ 0.2(=0.142\gamma^{-1}) \times h\ 24(=15.2\gamma^{-1})\text{mm}$

rotatable mirror accuracy : vertical= $19\mu\text{rad}$ , horizontal= $35\mu\text{rad}$

target position read accuracy:  $0.5\mu\text{m}$

filter wavelength region :  $550\pm 20\text{nm}$

light detector : PMT(Hamamatsu H1161)

$\gamma$ -detector : Air Cherenkov counter

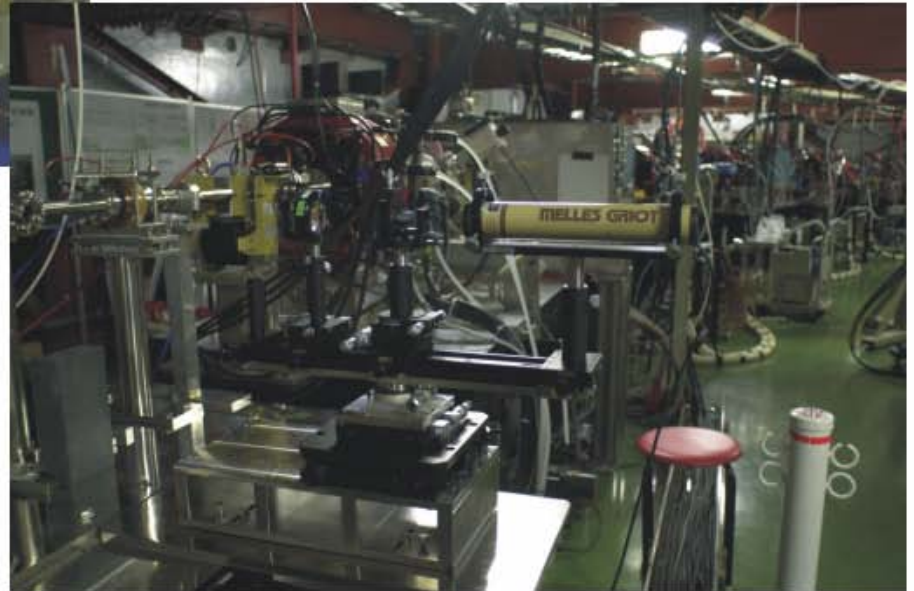
alignment accuracy :  $<100\mu\text{m}(\text{position})$  ,  $<42\mu\text{rad}(\text{angle})$

# the ODR chamber and the alignment laser



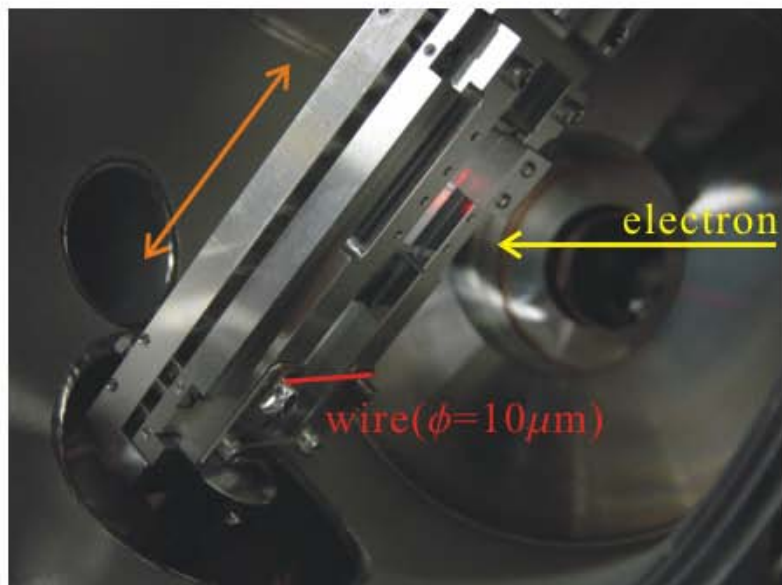
target chamber

alignment laser

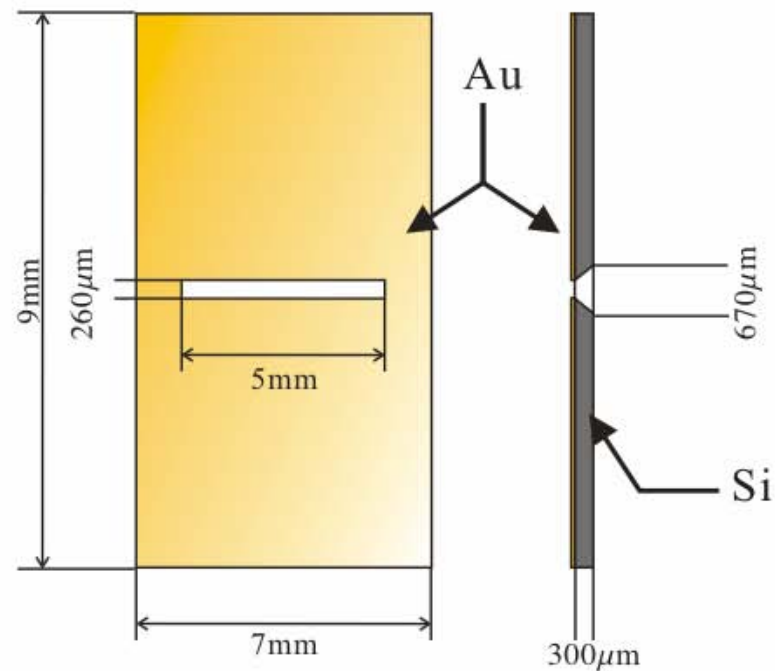




## Target and wire



### slit target



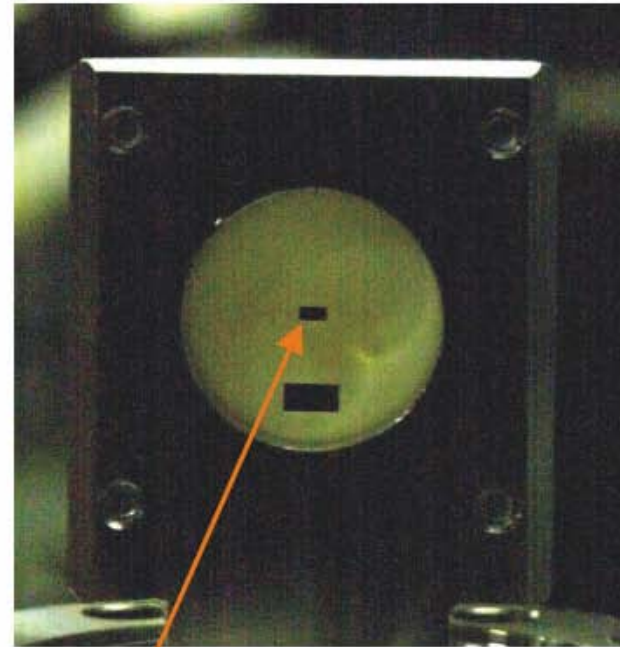
### Silicon wafer covered with gold

#### target property

silicon thickness	300 $\mu\text{m}$
gold foil thickness	$\sim 1\mu\text{m}$
edge uniformity	1–2 $\mu\text{m}$
average roughness	20nm
Maximum roughness	150nm

## SR mask

To avoid the contribution of synchrotron radiation(SR), we installed “SR mask” in front of the target chamber.



1x2mm hole on the ceramic plate

poster : THPLT067

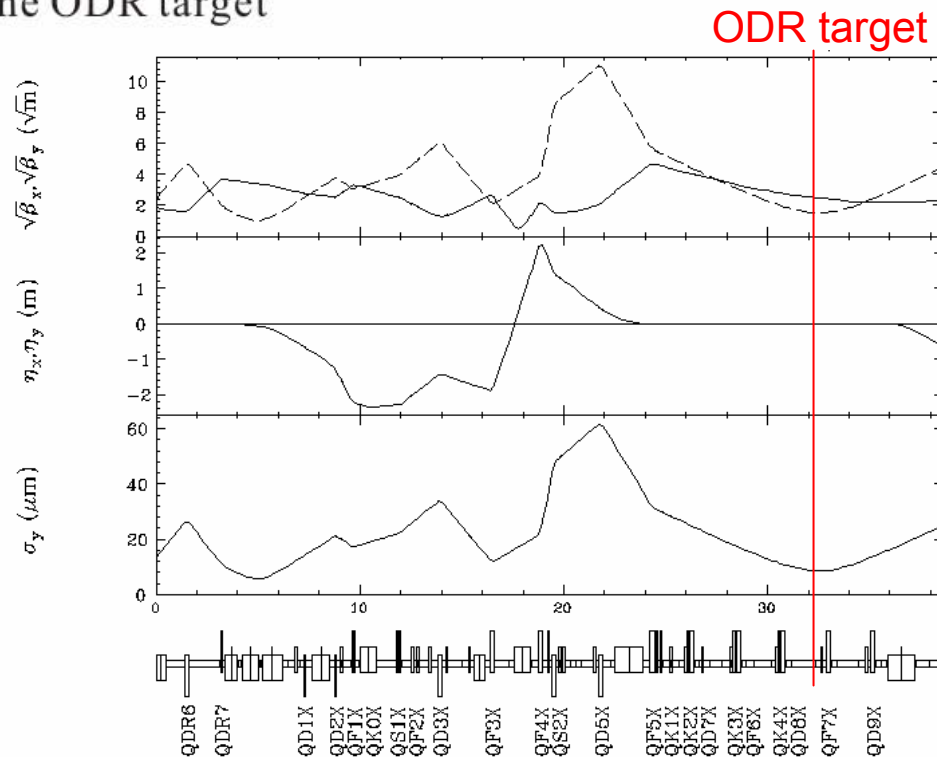
# Optics and Wire-scanning

In order to avoid SR background,  
the optics is all most quad and steer magnets after last bending magnet is turn off.

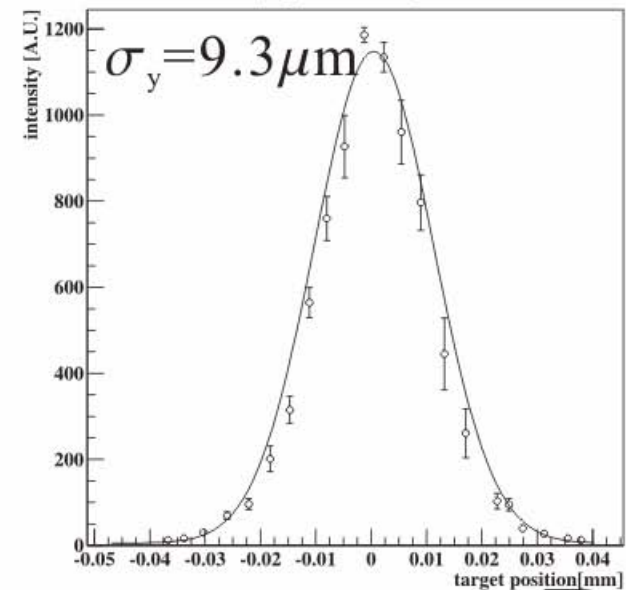
three different optics calculated by SAD were prepared

- $\sigma_y = 9\mu\text{m}$  (optics A)
- $\sigma_y = 15\mu\text{m}$  (optics B)
- $\sigma_y = 25\mu\text{m}$  (optics C)

at the ODR target



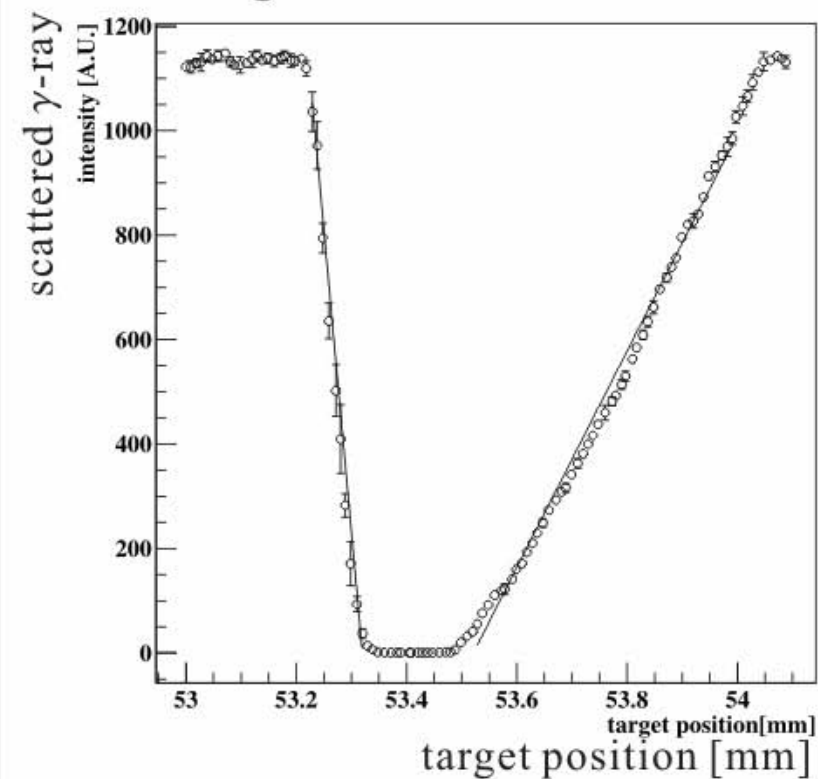
beam size measured  
by wire scanner  
(optics A)





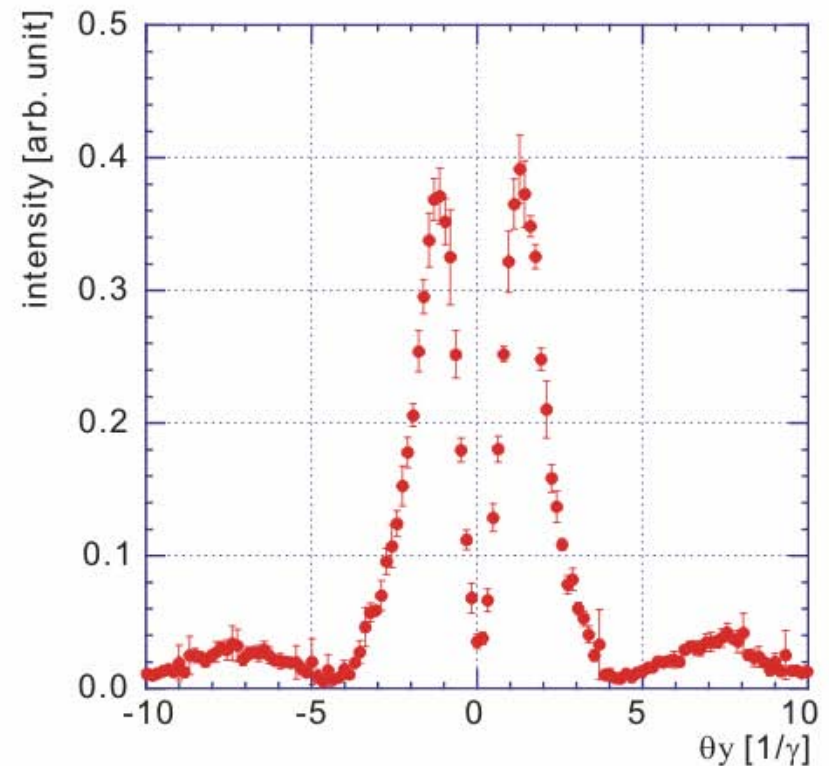
# Results

Target scan



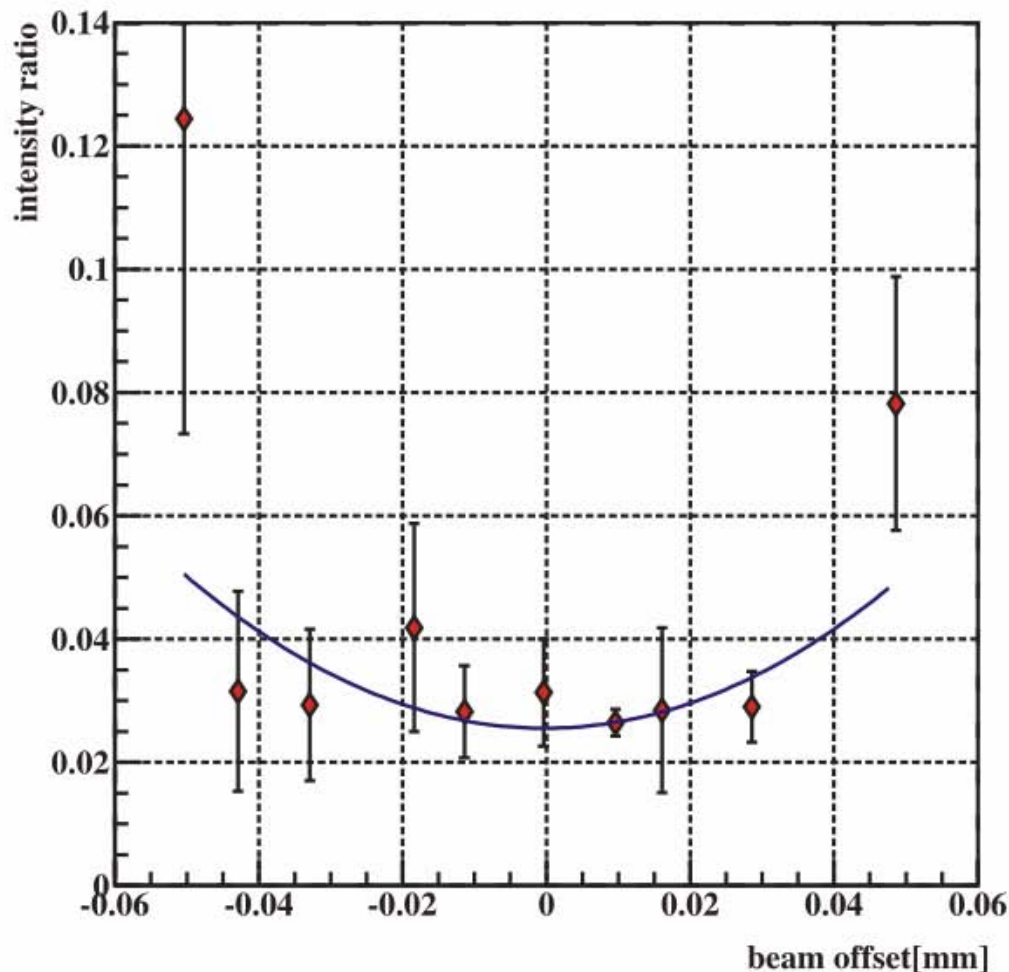
by this scan, slit center was obtained

ODR angular distribution



clear interference pattern by ODR was observed.

## Minimum-to-maximum ratio vs the target position (optics B)

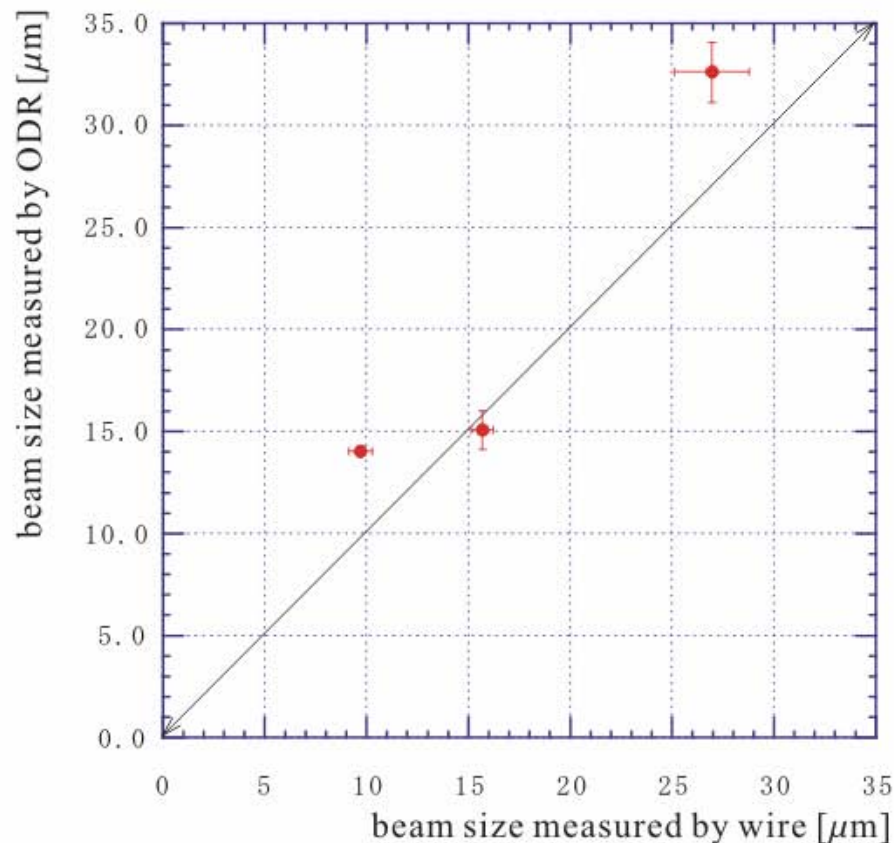


The solid line represents the parabolic fit.

From parabolic fit minimum-to-maximum intensity ratio was obtained.

Only statics error is shown.

## The comparison with measurements by the wire-scanning



Beam sizes measured by the ODR monitor has a sensitivity around  $20\mu\text{m}$  electron beam size.

Beam sizes measured by the ODR monitor were larger than measured by wire scanner.

It indicate that there are some systematic errors.

During this measurements, the beam extraction was not stable, because of the extraction kicker's timing jitter.



# Summary

- We performed the beam size measurements using ODR.
- The ODR interference pattern from the slit target was observed, and that has a sensitivity to electron beam size.
- From the comparison with beam sizes measured by the wire scanner, there are some systematic errors.
- During these measurements, the beam orbit was unstable because of the kicker. We should need a more intensive study. And in order to increase sensitivity, we will measure ODR with shorter wavelength.